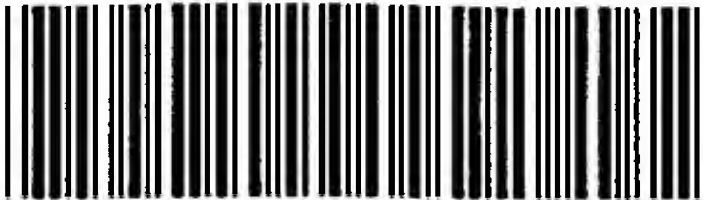


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/582,036	BURKART ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Tianjie Chen	2627	

SEARCHED			
Class	Subclass	Date	Examiner
720	675	12/12/2007	TJ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
720	675	12/12/2007	TJ

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Report	12/12/2007	TJ